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| Search Notes  | Application/Control No. 10824980 | Applicant(s)/Patent Under Reexamination DEWDNEY ET AL. |
| | Examiner Jaisle, Cecilia M | Art Unit 1624 |

| Notes | Date | Examiner |
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| Searched in STN by STIC | 07-19-06 | Cecilia Jaisle |
| Inventoir names searched in PALM | 8-28-06 | Cecilia Jaisle |
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| Class | SubClass | Date | Examiner |
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| | <p>Examiner</p> <p>Jaisle, Cecilia M</p> | <p>Art Unit</p> <p>1624</p> |

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